

CLAIMS

1. For use in connection a semiconductor device under test (DUT) having a plurality of leads to electronic test equipment, an interconnect assembly comprising:
 - a) a cable including a plurality of wires with at least one wire for sensing a signal from a DUT, at least one wire for a forcing signal to the DUT, and at least one wire for a guarding signal driven by the same electrical potential as the forcing signal,
 - b) a male connector including the plurality of wires, an outer metal coating surrounding the plurality of wires, and an insulating coating around the outer metal coating, and
 - c) a receptacle connector for receiving the male connector and plurality of wires with corresponding contacts.
2. The interconnect assembly as defined by claim 1 wherein the receptacle connector includes a metal housing, one contact of the receptacle connector for receiving the wire for a guarding signal being electrically connected to the metal housing of the receptacle connector.
3. The interconnect assembly as defined by claim 2 wherein the cable and the male connector include a plurality of wires for a forcing signal.
4. The interconnect assembly as defined by claim 2 wherein the receptacle connector is mountable on a printed circuit board of a test fixture with printed wiring of the printed circuit board connecting contacts of the receptacle connector to a socket of the test fixture.
5. The interconnect assembly as defined by claim 4 wherein the test fixture is housed within electronic test equipment.